ABSTRACT OF THE DISCLOSURE

When a built-in nonvolatile memory in a microcomputer is tested, a control program prestored in a boot ROM is run upon entering a test command from an external communication device; a test program is transferred from the external communication device to a built-in RAM through a communication circuit; a control of a CPU is switched to the built-in RAM after the test program has been transferred and a test is conducted on the nonvolatile memory; and a test result and a fail log are transferred to the external communication device through the communication circuit. Consequently, the built-in nonvolatile memory in the microcomputer can be checked without leaving the test program on the chip.